

16th International Workshop on DEPFET Detectors and Applications

Monday, 26 May 2014

PXD9 Update, Metal System Optimization, Sensor Testing - Tagungsraum (11:00 - 12:30)

-Conveners: Rainer Richter

time	[id] title	presenter
11:00	[35] PXD9 Production Status - first Yield Estimations	RICHTER, Rainer
11:30	[36] Testing of EMCM-3-2 on Wafer Level	RITTER, Andreas
12:00	[37] PXD9 wafer-level testing plans	Dr AVELLA, Paola